SEW

PATENT



Docket No.: 060188-0702

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Customer Number: 20277

Akio MISAKA : Confirmation Number: 8679

Application No.: 10/717,598 : Group Art Unit: 1756

Filed: November 21, 2003 : Examiner: ROSASCO, STEPHEN D

For: PHOTOMASK, PATTERN FORMATION METHOD USING PHOTOMASK AND MASK

DATA CREATION METHOD

INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached form PTO-1449. It is respectfully requested that the references be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

Each non-English language reference was first cited in a corresponding foreign application office action and its relevance discussed therein. A copy of the foreign office action, together with an English language version thereof, is attached for the Examiner's information.

10/717,598

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

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Date: September 8, 2005

Please recognize our Customer No. 20277 as our correspondence address.

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(ceb U 8 JOD2 m)					APPLICANT Akio MISAKA				
	((PT	O-1449)	RAPENASTI OF	FILING DATE GROUP November 21, 2003 1756				
U.S. PATENT DOCUMENTS									
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code2 (I known)		Publication Date MM-DD-YYYY	Name of Patentee or Appli Document	Name of Patentee or Applicant of Cited Document		Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
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FOREIGN PATENT DOCUMENTS EXAMINER'S Foreign Patent Document Publication Date Name of Patentee or Pages, Translation									
INITIALS	CITE NO.	Country Codes -Number 4 -Kind Codes (if known)		MM-DD-YYYY	Applicant of Cited Document	Columns, Lines Where Relevant Figures Appear		Yes	No
		WO 02/091079 A1		11/14/2002	MATSUSHITA ELECTRIC INDUSTRIAL CO., LTD.			JAPAN (w/English Abstract)	
		JP 06-019114		01/28/1994	HITACHI LTD. HITACHI ELECTRON ENG CO LTD.			JAPAN (w/English Abstract)	
		 	NO 01/04838 A1	01/18/2001	UNILEVER NV			X	
			JP 06-313964	11/08/1994	NIPPON TELEGR & TELEPH CORP <ntt></ntt>			JAPAN (w/English Abstract)	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)									
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.							
									
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1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.